



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application

Inventor(s): STEPHEN E. DEORNELLAS ET AL.
Appln. No.: 09/880,584
Confirm. No.: 8818
Filed: June 13, 2001
Title: METHOD FOR MINIMIZING THE CRITICAL
DIMENSION GROWTH OF A FEATURE ON A
SEMICONDUCTOR WAFER

PATENT APPLICATION

Art Unit: 1763
Examiner: George Goudreau

Customer No. 23910

RECEIVED
DEC 10 2003
TC 1700

CERTIFICATE OF MAILING UNDER 37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited in the United States Postal Service with sufficient postage as first class mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on December 2, 2003.

Thomas A. Ward (Attorney Signature)
Thomas A. Ward, Reg. No. 35,732
Signature Date: December 2, 2003

RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. § 1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Office Action mailed August 28, 2003, please amend the above-identified application as shown beginning on the following page.